

		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. : <b>BA-22855</b>		SERIAL NO. <b>10/603,291</b>	
<b>LIST OF REFERENCES CITED BY APPLICANT</b> (Use several sheets if necessary)				APPLICANT: <b>WENSYANG HSU, et al.</b>			
				FILING DATE: <b>June 25, 2003</b>		GROUP: <del>2878</del> <b>2873</b>	

  

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
Jp	AA	6,335,522B1	Jan. 2002	Asimada, et al.	250	201.3	
Jp	AB	6,154,326	Nov. 2000	Ueyanagi, et al.	359	819	
Jp	AC	6,055,220	Nov. 2000	Mamin, et al.	369	13.13	
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

  

FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL							
	AM							
	AN							
	AO							
	AP							

  

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)			
Jp	AR		Mansfield and Kino, "Solid immersion microscope" Appl. Phys. Lett. 57 (1990) pp. 2615, 2616
Jp	AS		Terris, Mamin, and Rugar "Near-field optical data storage using a solid immersion lens" Appl. Phys. Lett. 65 (1994) pp. 388-390
Jp	AT		Lane, "Fabrication of Sub-micron Optical Apertures by an Over-Electroplating Method" ISOM (2001) pp. 252-253

  

EXAMINER <b>JACK DINH</b>	DATE CONSIDERED <b>05/20/04</b>
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.